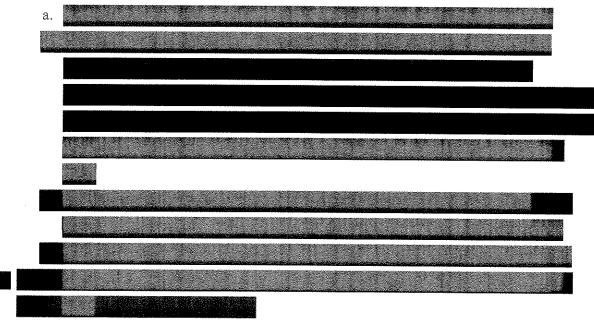
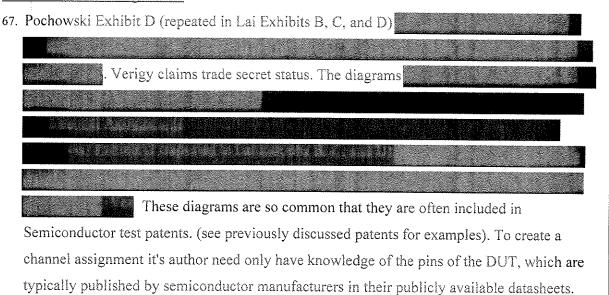


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MOUNT & STOELKER, P.C. RIVERPARK TOWER, SUITE 1650 65. As a specific example I review the Hynix HY27UH08AG(5/D)M Series 16Gbit NAND Flash device. Attached as exhibit SS is a true and correct copy of the HY27UH08AG(5/D)M Series 16Gbit NAND Flash device upon which this analysis is based. ("the Datasheet").



NAND Channel Assignments



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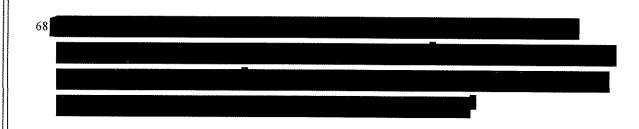
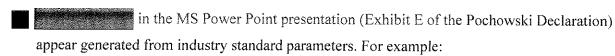


Exhibit E: Mock Presentation to Simulations

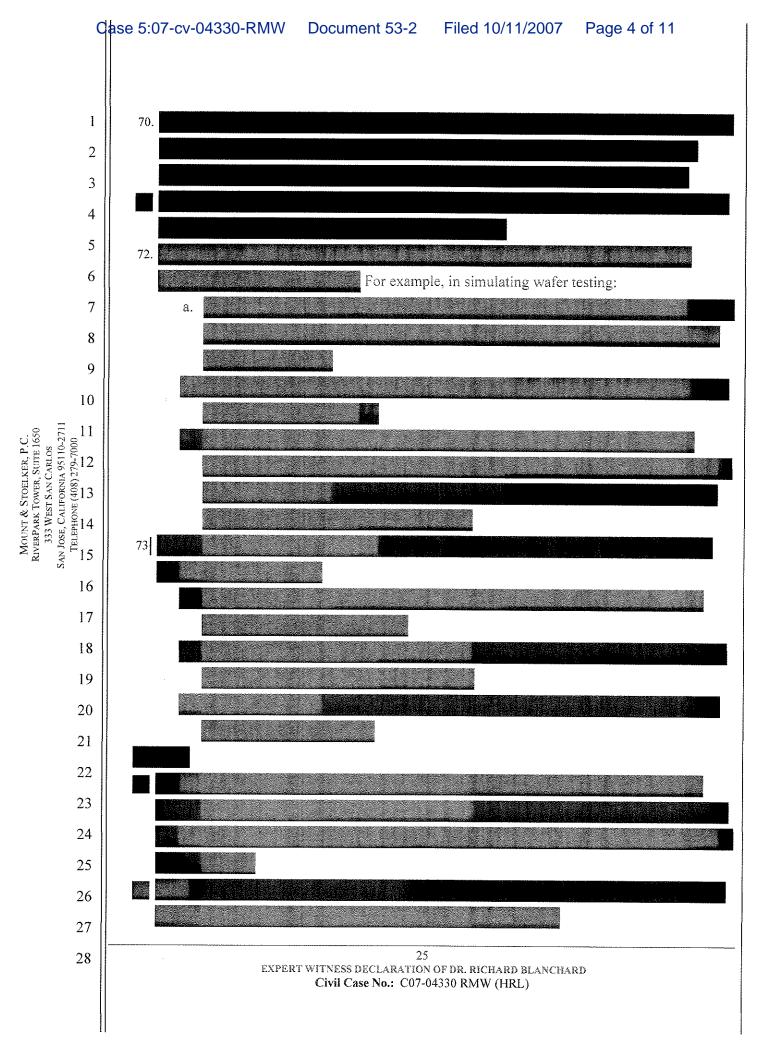


- a. The standard diameter of a probe card is 400mm. From this knowledge one can estimate that a typical trace length from any circuitry mounted on the probe (such as Flash Enahncer) to the wafer is approximately eight (8) inches.
- b. The typical resistance and capacitance for a FET switch are 5 ohms and 1 Pico Farad. respectively.
- c. DUT input capacitance is typically modeled as 5 pico Farads. This standard value can be confirmed from IBIS (Input/Output Buffer Information Specification) models commonly available in the industry. An article describing the IBIS models can be found is attached as Exhibit JJ, which was downloaded from the World Wide Web at http://www.eetasia.com/ARTICLES/2005JUN/A/2005JUN01 CTRLD AN08.PDF?S OURCES=DOWNLOAD.
- d. Many NAND flash testers today operate in the range of 50 100 Mega Hertz. This specification is known in the industry and is also available on many website. Such an assumption is also consistent with known Flash Memory chip speeds, which are readily available in datasheets from any Flash Memory manufacturer's website. See http://www.evaluationengineering.com/archive/articles/1000focus.htm for an example of the V4400 100MHz test speed. A copy of the article is attached as Exhibit RR.

See http://en.wikipedia.org/wiki/Switch for a description of switches and how they work.

Blanchard Declaration para A, exhibit E, F. (Honeywell and other semiconductor switch datasheets)

Blanchard Declaration, para B, exhibits G, H (micron patents on probe card multiplexing)



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- 80. This type of switch technology is well known in the industry. Data sheets from other companies that discuss similar switch technology are listed below.
 - a. Peregrine SP4T, SP7T (true and correct copy attached as Exhibit L)
 - b. Hetlite SP4T (true and correct copy attached as Exhibit M)
 - c. RFMD SP4T (true and correct copy attached as Exhibit N)
 - d. Skyworks SP4T (true and correct copy attached as Exhibit O)

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- e. Tyco SP4T (true and correct copy attached as Exhibit P)
- 81. Flash Enhancer is not derived from the Chameleon ASIC. A detailed discussion of this can be found in the section below.
- 82. The Disclosure describes desires for problems that an application specific integrated circuit ("ASIC") could solve for testing if mounted on a probe card. Here, I consider whether each assertion of the Disclosure is publicly available or well known in the industry, and whether each assertion is now present in Flash Enhancer. I consider each section of the Disclosure in turn.

Section B of the Disclosure

83.

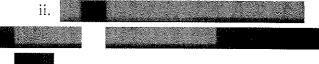
- i. This is not an invention. Fan out of bi-directional I/O (data) lines is disclosed in the '112 Micron Patent, and the '225 FormFactor patent.
- ii. Flash Enhancer includes this capability.

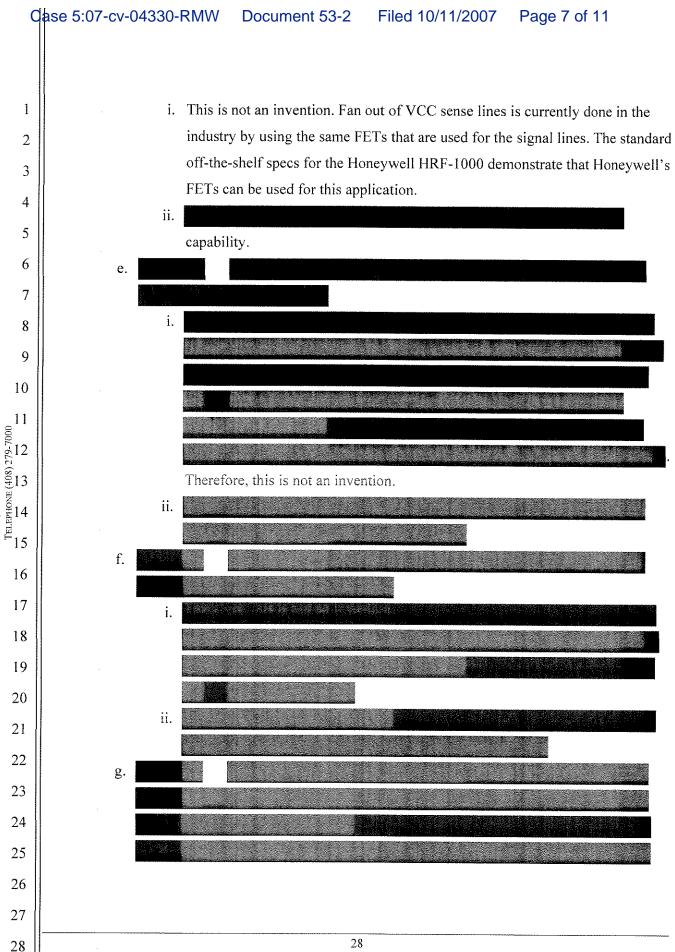


- i. This is not an invention. The ability to disconnect a shorted/failed DUT is disclosed in the '112 Micron Patent, and the '225 FormFactor patent.
- ii. Flash Enhancer includes this capability.



i. This is not an invention. Fan out of power supplies is commonly done in the ATE industry today through the use of mechanical relays, photoMOS relays, and FET switches placed on load boards and probe cards.





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